## Notice of References Cited Application/Control No. 10/058,721 Examiner Huy Q Phan Applicant(s)/Patent Under Reexamination REHKOPF, THOMAS W. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0042266 A1	04-2002	Heyward et al.	455/414
	В	US-6,522,875 B1	02-2003	Dowling et al.	455/414.3
	O	US-2002/0006787	01-2002	Darby, George Eugene	455/419
	۵	US-6,484,096 B2	11-2002	Wong et al.	701/213
	Е	US-2002/0068592 A1	06-2002	Hutcheson et al.	455/501
	F	US-2002/0045456 A1	04-2002	Obradovich, Michael L.	455/457
	G	US-2002/0082774 A1	06-2002	Bloebaum, Leland Scott	701/213
	Ι	US-2004/0054890 A1	03-2004	Vasseur, Francois-Joseph	713/156
	_	US-2002/0164998 A1	11-2002	Younis, Saed	455/456
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р				,	
	Q					
	R					
	S					
	۲					

## **NON-PATENT DOCUMENTS**

	NON-PATENT DOCUMENTS						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	>						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.